N-channel TrenchMOS logic level FET Rev. 01 — 23 August 2007

Product data sheet

Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

1.2 Features

- Logic level threshold
- Optimized for use in DC-to-DC converters
- 100 % R_G tested

- Lead-free package
- Very low switching and conduction losses
- 100 % ruggedness tested

1.3 Applications

- DC-to-DC converters
- Voltage regulators

- Switched-mode power supplies
- PC motherboards

1.4 Quick reference data

- $V_{DS} \le 30 \text{ V}$
- \blacksquare R_{DSon} \leq 9.9 m Ω

- $I_D \le 63 \text{ A}$
- $Q_{GD} = 3.2 \text{ nC (typ)}$

Pinning information

Table 1. **Pinning**

	9		
Pin	Description	Simplified outline	Symbol
1, 2, 3	source (S)		_
4	gate (G)	mb	B
mb	mounting base; connected to drain (D)	1 2 3 4	mbb076 S
		SOT669 (LFPAK)	



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3. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
PH9930L	LFPAK	plastic single-ended surface-mounted package (Ifpak); 4 leads	SOT669

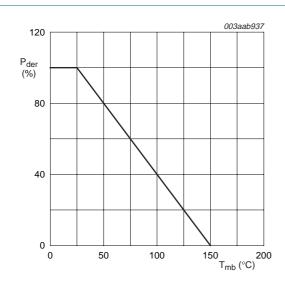
4. Limiting values

Table 3. Limiting values

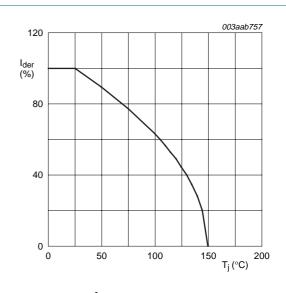
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	25 °C ≤ T _j ≤ 150 °C	-	30	V
V_{DGR}	drain-gate voltage (DC)	$25~^{\circ}\text{C} \le \text{T}_{j} \le 150~^{\circ}\text{C}; \text{R}_{\text{GS}} = 20~\text{k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-	±20	V
I_D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 2</u> and <u>3</u>	-	63	Α
		T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 2	-	39	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$; see Figure 3	-	214	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 1</u>	-	62.5	W
T _{stg}	storage temperature		-55	+150	°C
Tj	junction temperature		-55	+150	°C
Source-o	drain diode				
Is	source current	T _{mb} = 25 °C	-	52	Α
I _{SM}	peak source current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \ \mu s$	-	208	Α
Avalance	ne ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	unclamped inductive load; I_D = 33 A; t_p = 0.08 ms; $V_{DS} \le$ 30 V; R_{GS} = 50 Ω ; V_{GS} = 10 V; starting at T_j = 25 °C	-	53	mJ

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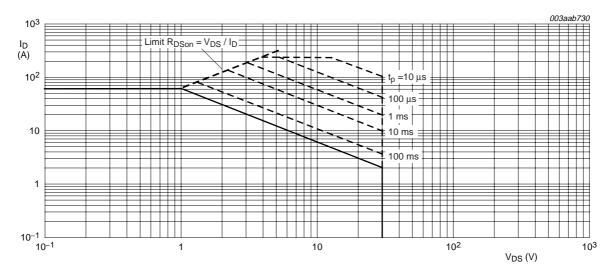
 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100~\%$ Fig 1. Normalized total power dissipation as a function of mounting base temperature



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature

3 of 12



 T_{mb} = 25 °C; I_{DM} is single pulse

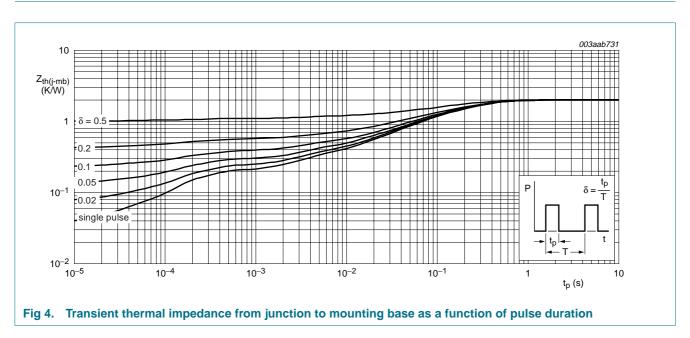
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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6. Characteristics

Table 5. Characteristics

 $T_j = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 250 \mu\text{A}; V_{GS} = 0 V$				
voltage	voltage	T _j = 25 °C	30	-	-	V
		T _j = −55 °C	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; see <u>Figure 9</u> and <u>10</u>				
		T _j = 25 °C	1.3	1.7	2.15	V
		T _j = 150 °C	0.8	-	-	V
		T _j = −55 °C	-	-	2.6	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}$				
		T _j = 25 °C	-	-	1	μΑ
		T _j = 150 °C	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = \pm 16 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	100	nΑ
R_G	gate resistance	f = 1 MHz	-	0.56	-	Ω
R _{DSon}	drain-source on-state	$V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; see Figure 6 and 8				
	resistance	T _j = 25 °C	-	7.2	9.9	$m\Omega$
		T _j = 150 °C	-	11.9	15.8	$m\Omega$
		$V_{GS} = 4.5 \text{ V}$; $I_D = 25 \text{ A}$; see Figure 6 and 8	-	10.5	13.5	$m\Omega$
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	13.3	-	nC
Q_{GS}	gate-source charge	see Figure 11 and 12	-	4.8	-	nC
Q _{GS1}	pre-V _{GS(th)} gate-source charge		-	3.0	-	nC
Q _{GS2}	post-V _{GS(th)} gate-source charge		-	1.8	-	nC
Q_{GD}	gate-drain charge		-	3.2	-	nC
$V_{GS(pl)}$	gate-source plateau voltage		-	2.72	-	V
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 12 \text{ V}; f = 1 \text{ MHz};$	-	1565	-	pF
C _{oss}	output capacitance	see Figure 14	-	355	-	pF
C _{rss}	reverse transfer capacitance		-	186	-	pF
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 0 \text{ V}; f = 1 \text{ MHz}$	-	1839	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 Ω ; V_{GS} = 4.5 V;	-	20	-	ns
t _r	rise time	$R_G = 5.6 \Omega$		41	-	ns
t _{d(off)}	turn-off delay time			15	-	ns
t _f	fall time		-	25	-	ns
Source-d	drain diode					
V_{SD}	source-drain voltage	I _S = 25 A; V _{GS} = 0 V; see <u>Figure 13</u>	-	0.89	1.16	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V}$	-	43	-	ns
Q _r	recovered charge		-	15	-	nC

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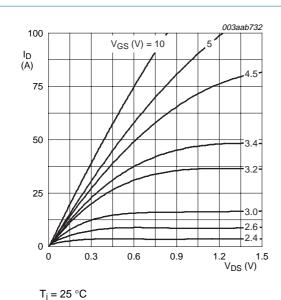


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

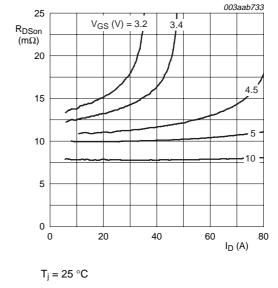
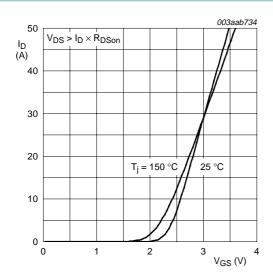
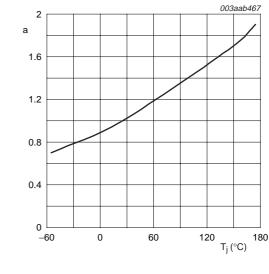


Fig 6. Drain-source on-state resistance as a function of drain current; typical values



 $T_i = 25 \,^{\circ}\text{C}$ and 150 $^{\circ}\text{C}$; $V_{DS} > I_D \times R_{DSon}$

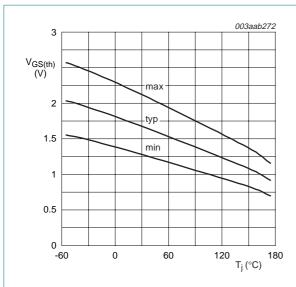


 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values

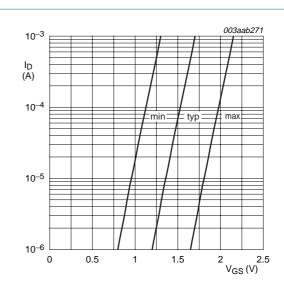
Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature

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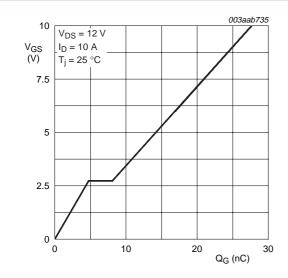
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25~^{\circ}C;~V_{DS} = 5~V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}$

Fig 11. Gate-source voltage as a function of gate charge; typical values

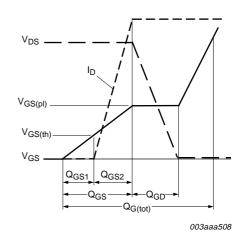


Fig 12. Gate charge waveform definitions

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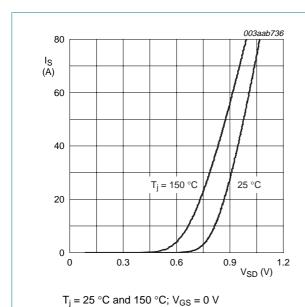
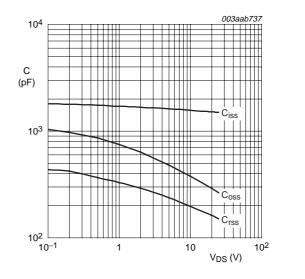


Fig 13. Source current as a function of source-drain voltage; typical values



 $V_{GS} = 0 V$; f = 1 MHz

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

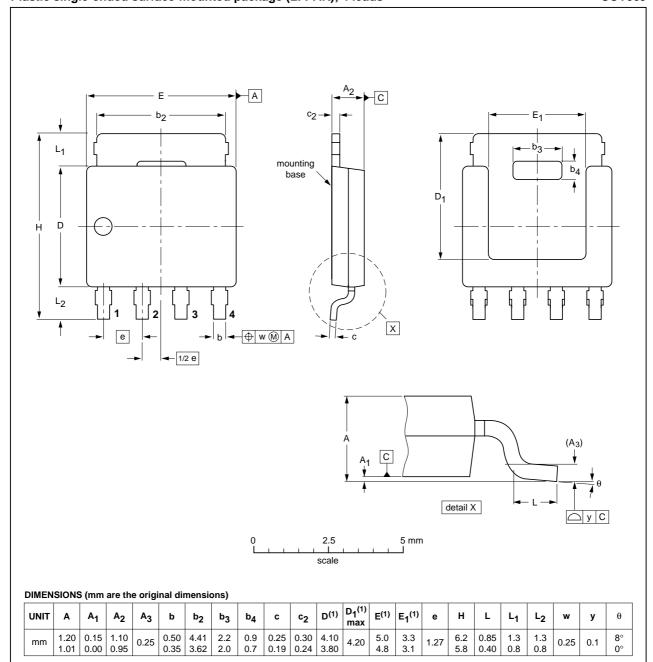
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Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES		EUROPEAN ISSU	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA			ISSUE DATE	
SOT669		MO-235				04-10-13 06-03-16	

Fig 15. Package outline SOT669 (LFPAK)

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8. Revision history

Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH9930L_1	20070823	Product data sheet	-	-

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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